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Date	August 10, 2005	CENTRAL FAX CENTER
To ·	Examiner Houshang SAFAIPOUR	AUG 1 0 2005
Of	PTO Group Art Unit 2622	
Fax	(571) 273-8300	

From Nataliya Dvorson Reg. No. 56,616

Forwarding Copy of PTO-1449 filed on April 2, 2001

Our Ref Q61184 Appln No 09/822,518

Conf No 7498 Inventors Toshitaka AGANO

Pages 2 (including cover sheet)

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This fax filing includes:

Subject

- This cover sheet {one page}
- 2. copy of PTO-1449 filed with Information Disclosure Statement on April 2, 2001 (one page)

Dear Examiner Safaipour:

Further to our conversation today, please find enclosed a clean copy of the form PTO-1449. As discussed, the two crossed out references are discussed in the specification (see IDS as filed and Amendment under 37 C.F.R. § 1.111). The third reference not initialed (Abstract 02-164067) was provided and is available in the IFW. Please initial and return the form PTO-1449. If you have any questions, please feel free to contact me at (202) 857-3228.

.Thank you,

Natalya Dvorson

Serial No.: NOT YET ASSIGNED Atty. Docket No. Form PTO-1449 U.S. Department of Commerce (Rev. 2-32) Patent & Trademark Office Confirmation No.: NOT YET ASSIGNED Q61184 INFORMATION DISCLOSURE STATEMENT Applicant: Toshitaka AGANO (Use several sheets if necessary) Filing Date: Group: April 2, 2001 U.S. PATENT DOCUMENTS Examiner Document Number Date Class Name Sub-Filing Date Initial Class (if appropriate) 4,803,359 02/07/89 HOSOI et al 250 327.2 FOREIGN PATENT DOCUMENTS Document Date Country Class Sub-Translation Yes/No class 59-211263 11/30/84 JP H01L 27/14 2-164067 06/25/90 JΡ HOIL 27/146 1-216290 08/30/89 JΡ GOIT 1/24 0 898 421 A2 02/24/99 EP H04N 5/30 9-222114 08/26/97 ЛР 47/00 F16B 92/06501 04/16/92 WO HOIL 27/14 OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Material Parameters In Thick Hydrogenated Amorphous Silicon Radiation Detectors, University of California, Berkeley IEEE, Vol. 36, No. 2, April 1989, Metal/Amorphous Silicon Multilayer Radiation Detectors, YUJIRO NARUSE and TAMOTSU HATAYAMA Abstract, 02-164067, 06/25/60 Abstract, 01-216290, 08/30/89 **EXAMINER:** DATE CONSIDERED: EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication.